

G-RAD Workshop - Grenoble Radiation Testing of semiconductor devices and systems



Contribution ID: 23

Type: not specified

Q&A Session on emergent needs and limitations of the current offer for radiation testing facilities

Wednesday, 9 December 2020 17:00 (30 minutes)

Presenters: BOUDOU, Caroline (Institut Laue-Langevin); CAPRIA, Ennio (European Synchrotron (ESRF))

Session Classification: Session 2 - Atmospheric and terrestrial applications